

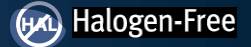
# EPC2206 – Automotive 80 V (D-S) Enhancement Mode Power Transistor

$V_{DS}$ , 80 V

$R_{DS(on)}$ , 2.2 mΩ

$I_D$ , 90 A

AEC-Q101



Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

## Maximum Ratings

PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	80	V
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ )	90	A
	Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300 \mu\text{s}$ )	390	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature	-40 to 150	

## Thermal Characteristics

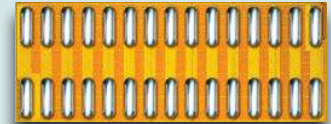
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.4	$^\circ\text{C}/\text{W}$
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	1.1	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	42	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.

## Static Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 500 \mu\text{A}$	80			V
$I_{DSS}$	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 80 \text{ V}$		20	200	$\mu\text{A}$
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 6 \text{ V}$ , $T_J = 25^\circ\text{C}$		0.02	4	mA
	Gate-to-Source Forward Leakage <sup>#</sup>	$V_{GS} = 6 \text{ V}$ , $T_J = 125^\circ\text{C}$		0.1	9	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		20	200	$\mu\text{A}$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 13 \text{ mA}$	0.7	1.2	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$ , $I_D = 29 \text{ A}$		1.8	2.2	mΩ
$V_{SD}$	Source-Drain Forward Voltage <sup>#</sup>	$I_S = 0.5 \text{ A}$ , $V_{GS} = 0 \text{ V}$		1.5		V

All measurements were done with substrate connected to source.  
<sup>#</sup> Defined by design. Not subject to production test.



**EPC2206** eGaN® FETs are supplied only in passivated die form with solder bars.  
 Die Size: 6.05 x 2.3 mm

## Applications

- 48 V Automotive Power
- Open Rack Server Architectures
- High Power Density DC-DC Converters
- Isolated Power Supplies
- Class D Audio
- Low Inductance Motor Drive

## Benefits

- Ultra High Efficiency
- No Reverse Recovery
- Ultra Low  $Q_G$
- Small Footprint



Dynamic Characteristics# ( $T_j = 25^\circ\text{C}$  unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$C_{ISS}$	Input Capacitance	$V_{DS} = 40\text{ V}, V_{GS} = 0\text{ V}$		1610	1940	pF
$C_{RSS}$	Reverse Transfer Capacitance			15		
$C_{OSS}$	Output Capacitance			1100	1650	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }40\text{ V}, V_{GS} = 0\text{ V}$		1450		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			1790		
$R_G$	Gate Resistance			0.3		$\Omega$
$Q_G$	Total Gate Charge	$V_{DS} = 40\text{ V}, V_{GS} = 5\text{ V}, I_D = 29\text{ A}$		15	19	nC
$Q_{GS}$	Gate-to-Source Charge	$V_{DS} = 40\text{ V}, I_D = 29\text{ A}$		4.1		
$Q_{GD}$	Gate-to-Drain Charge			3		
$Q_{G(TH)}$	Gate Charge at Threshold			2.7		
$Q_{OSS}$	Output Charge		$V_{DS} = 40\text{ V}, V_{GS} = 0\text{ V}$		72	
$Q_{RR}$	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

# Defined by design. Not subject to production test.

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Figure 1: Typical Output Characteristics at 25°C

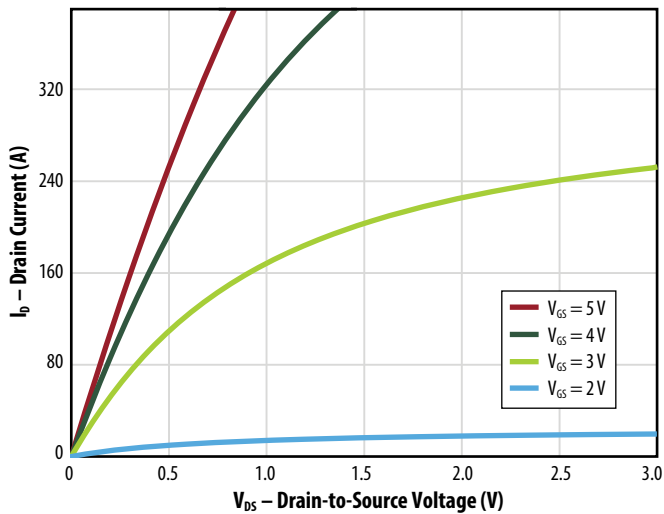


Figure 2: Typical Transfer Characteristics

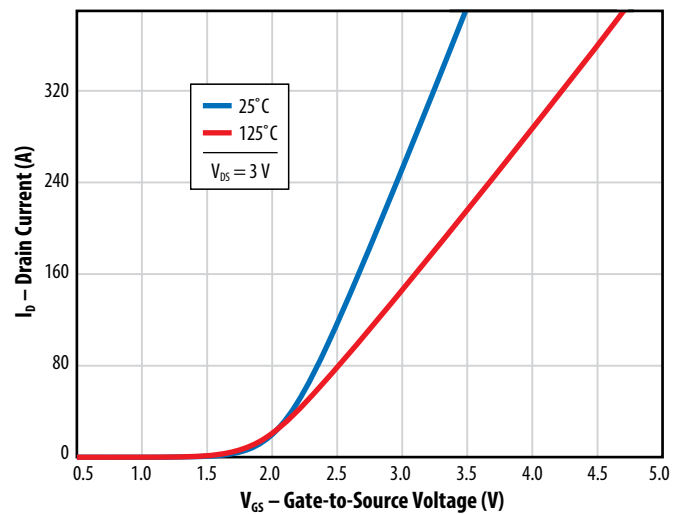


Figure 3:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain Currents

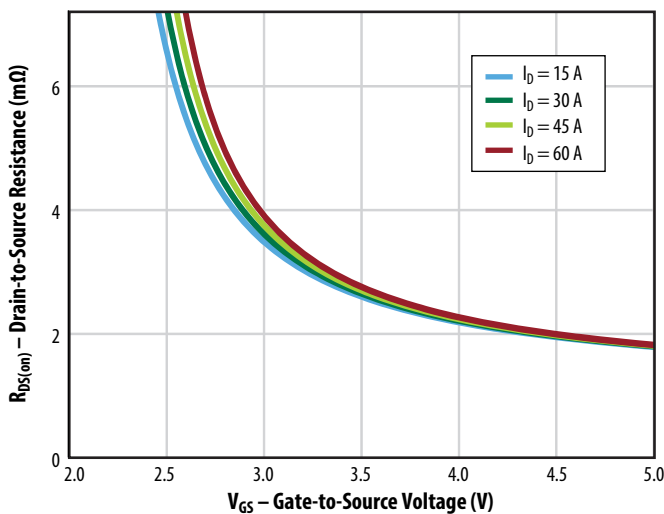


Figure 4:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures

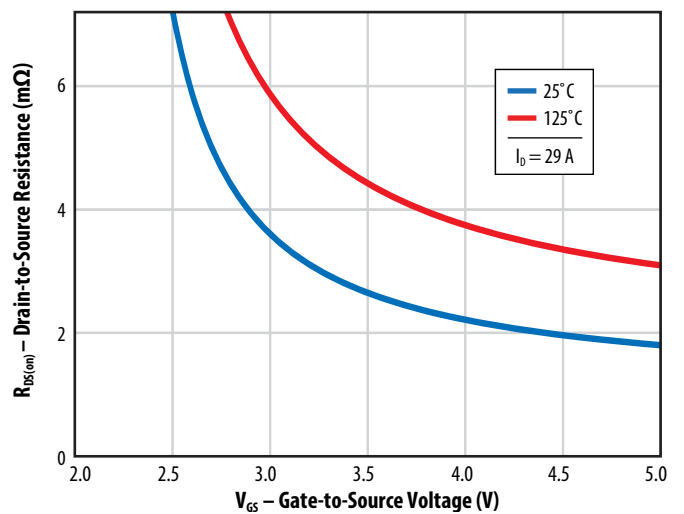


Figure 5a: Typical Capacitance (Linear Scale)

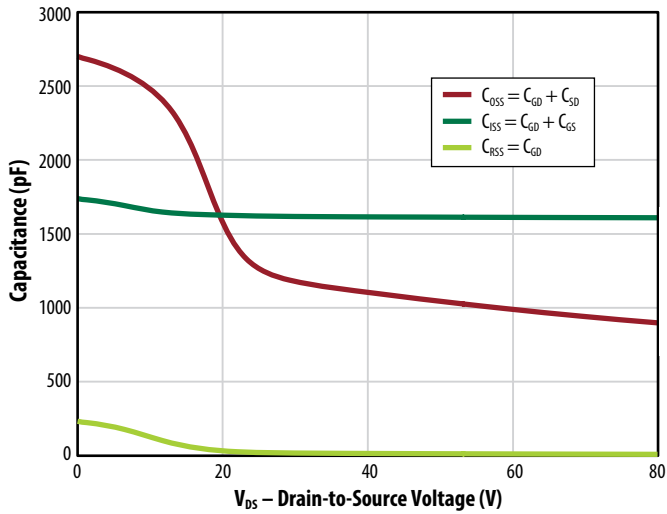


Figure 5b: Typical Capacitance (Log Scale)

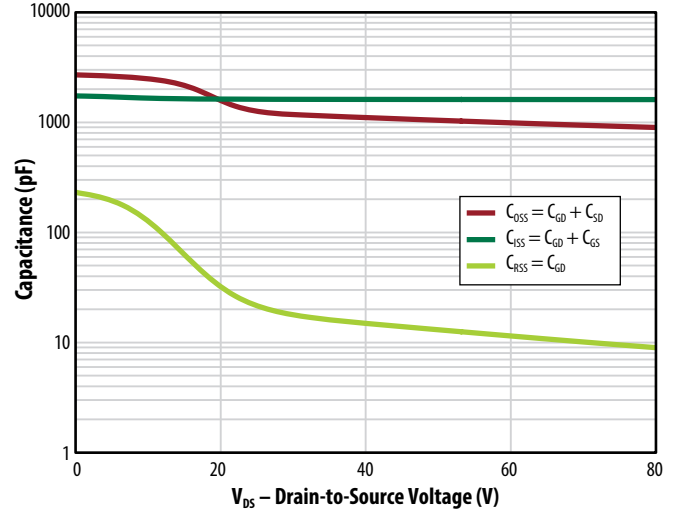


Figure 6: Typical Output Charge and C\_oss Stored Energy

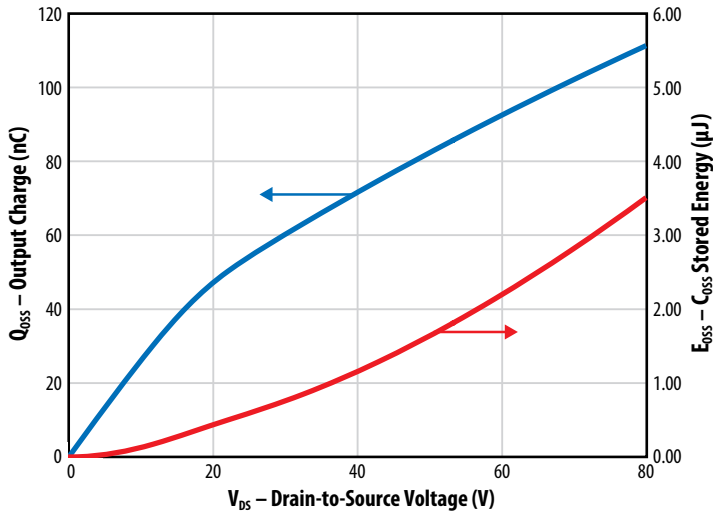


Figure 7: Typical Gate Charge

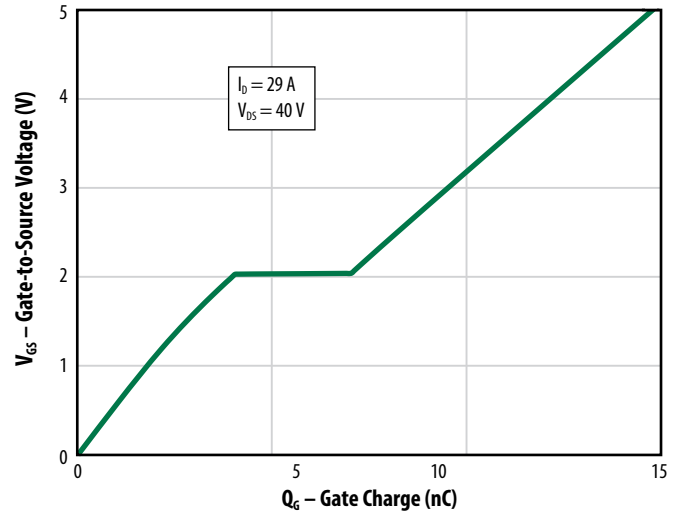


Figure 8: Reverse Drain-Source Characteristics

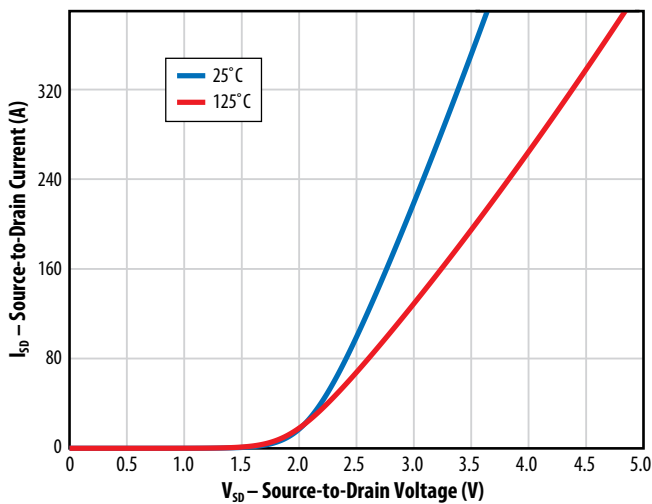
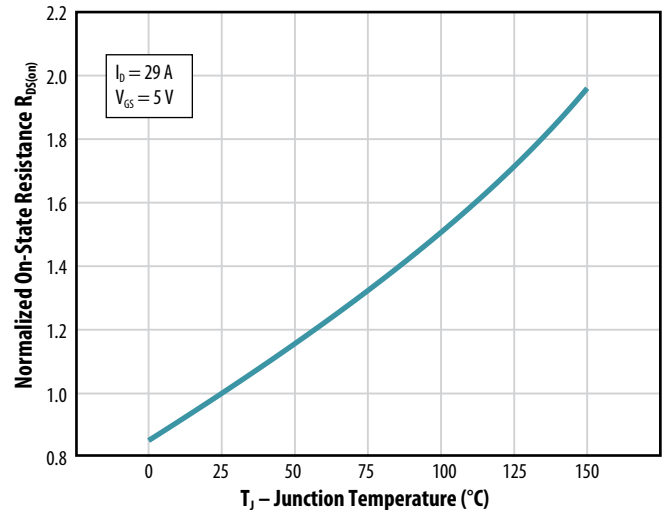


Figure 9: Normalized On-State Resistance vs. Temperature



Note: Negative gate drive voltage increases the reverse drain-source voltage.  
EPC recommends 0V for OFF.

Figure 10: Normalized Threshold Voltage vs. Temperature

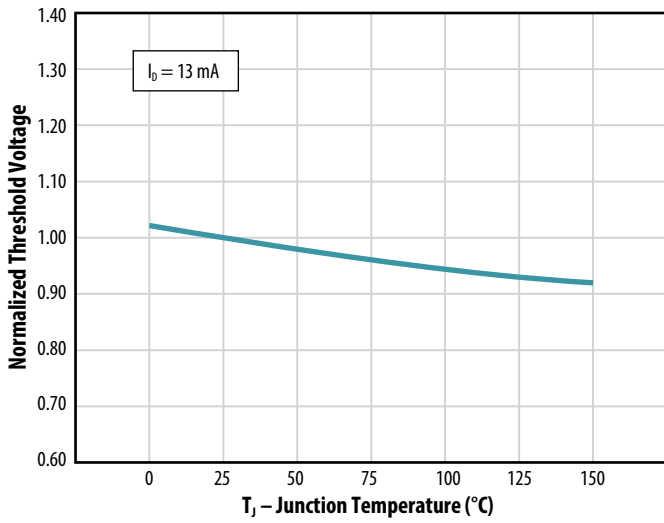


Figure 11: Safe Operating Area

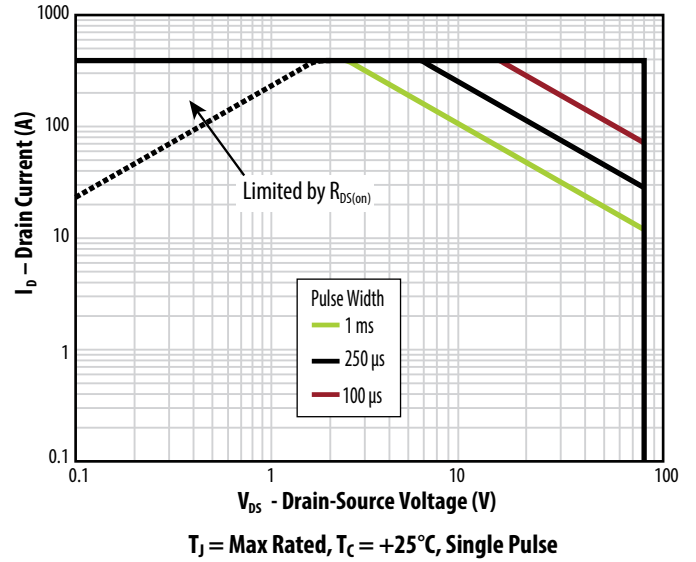
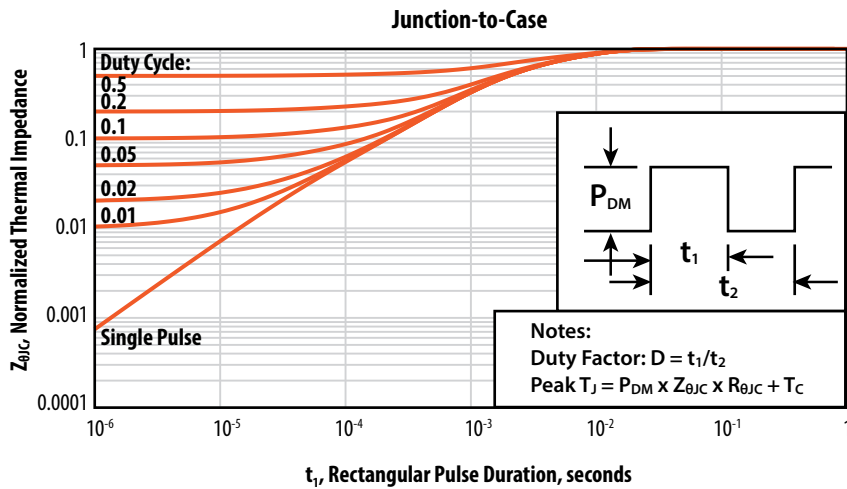
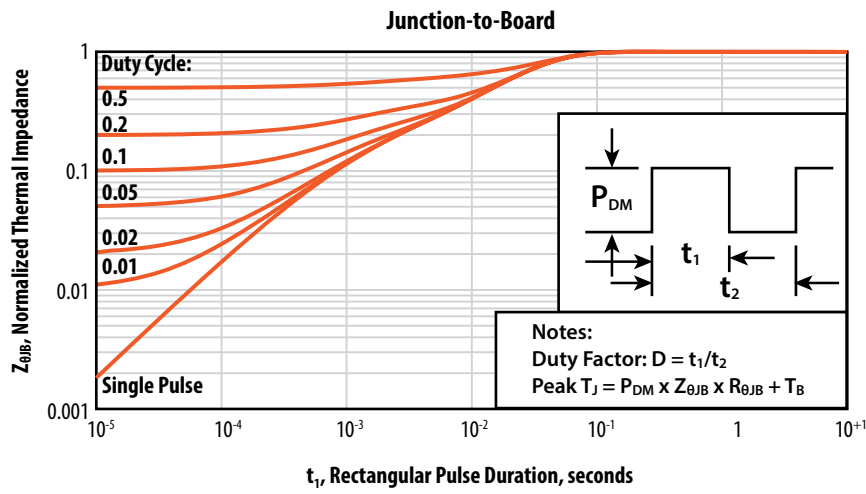
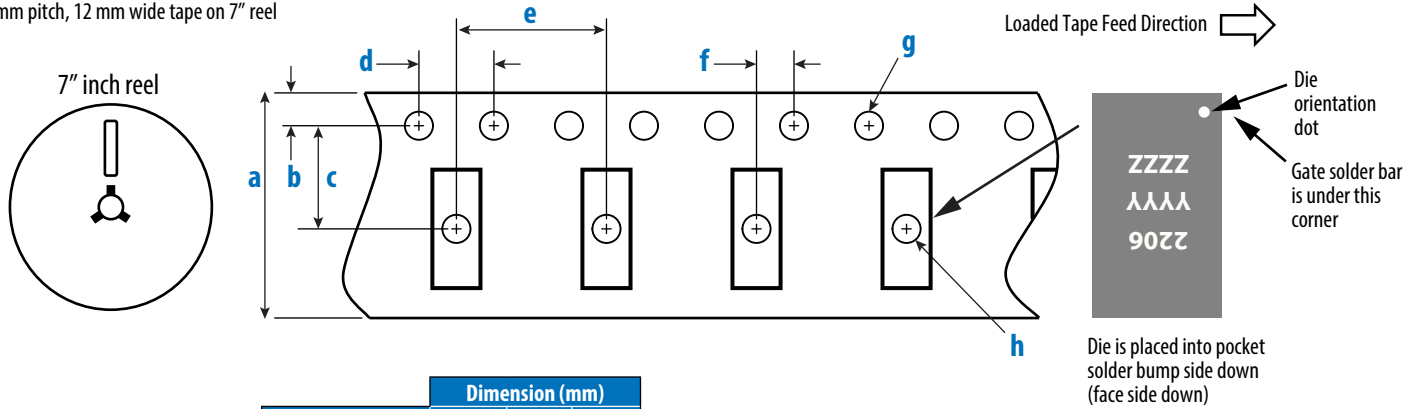


Figure 12: Transient Thermal Response Curves



**TAPE AND REEL CONFIGURATION**

8 mm pitch, 12 mm wide tape on 7" reel

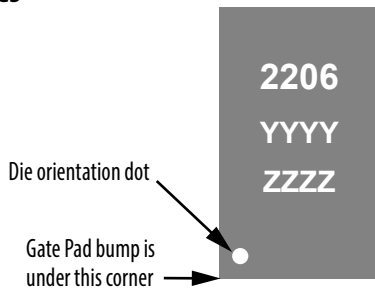


EPC2206 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
a	12.00	11.90	12.30
b	1.75	1.65	1.85
c (Note 2)	5.50	5.45	5.55
d	4.00	3.90	4.10
e	8.00	7.90	8.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60
h	1.50	1.50	1.75

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

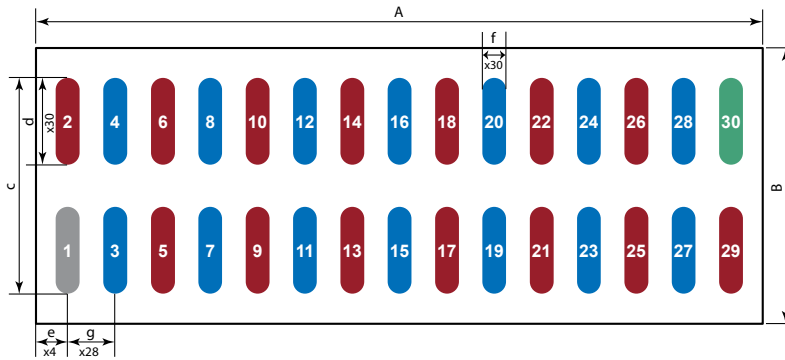
**DIE MARKINGS**



Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2206	2206	YYYY	ZZZZ

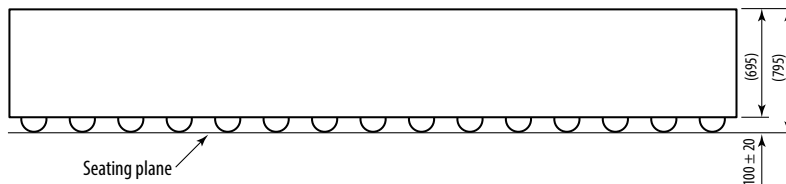
**DIE OUTLINE**

Solder Bump View



DIM	Micrometers		
	MIN	Nominal	MAX
A	6020	6050	6080
B	2270	2300	2330
c	2047	2050	2053
d	717	720	723
e	210	225	240
f	195	200	205
g	400	400	400

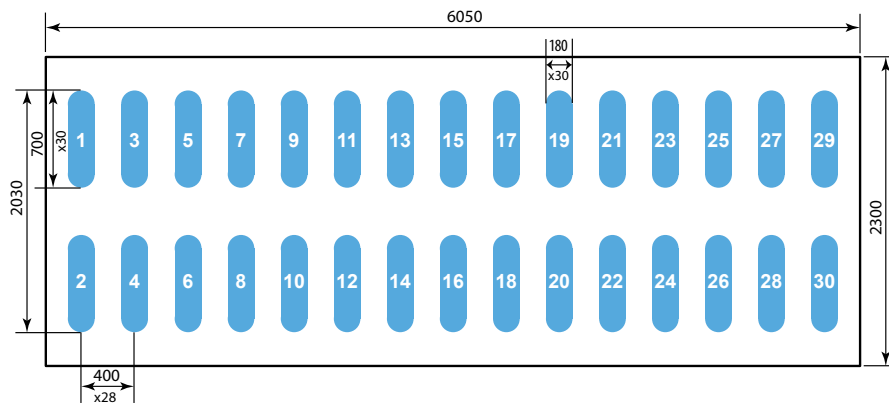
Side View



Pad 1 is Gate;  
**Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29 are Source;**  
**Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;**  
**Pad 30 is Substrate.\***

\*Substrate pin should be connected to Source

**RECOMMENDED LAND PATTERN**  
(units in  $\mu\text{m}$ )

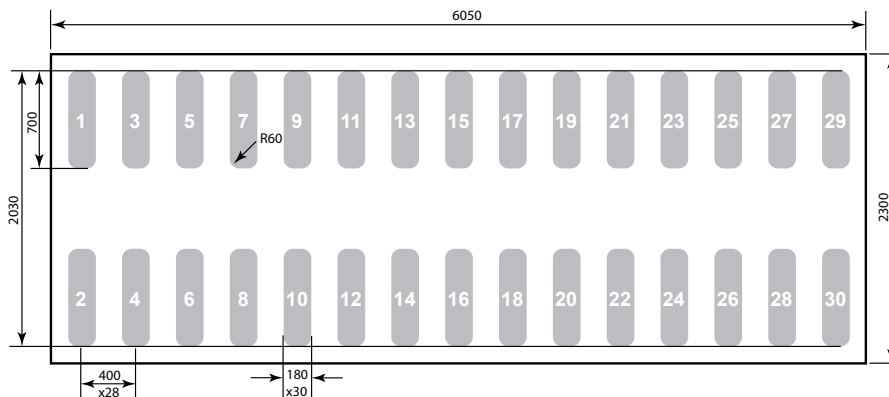


Land pattern is solder mask defined.

- Pad 1 is Gate;
- Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29 are Source;
- Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;
- Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

**RECOMMENDED STENCIL DRAWING**  
(units in  $\mu\text{m}$ )



Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at <https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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